

<b>Notice of References Cited</b>	Application/Control No. 10/563,100	Applicant(s)/Patent Under Reexamination SONOBE ET AL.	
	Examiner Earl N. Taylor	Art Unit 2818	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-			
	C	US-			
	D	US-			
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Kim, Jong Kyu et al., Microstructural study of Pt contact on p-type GaN, Journal of Vauum Science and Technology B, Vol. 21, Issue 1, pages 87-90, January 2003
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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